
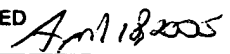
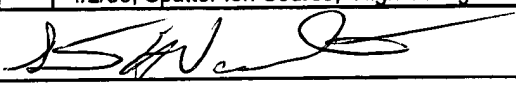




F-7904

Form PTO-1449 (Rev. 7-80) 42-44F (F-49)		U.S. Department of Commerce Patent and Trademark Office		Atty. Docket No.: F-7904		Serial No.: 10/655,896	
INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)				Applicant: Manfred FRIEDRICH, et al.		Filing Date: September 4, 2003	
				Group: 1753			
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
TRANSLATION KEY: * English Abstract. ^F Concise statement of relevance provided in foreign search report. ^C Concise statement of relevance provided in specification. ^S Concise statement of relevance provided in IDS. ^P Relevant portion of reference translated. ^O English abstract only - copy of reference in pct search.							
OTHER INFORMATION DISCLOSURE CITATIONS (Including Author, Title, Date, Pertinent Pages, Etc.)							
SHV		12/2/1990 "The AMS System at the Shanghai Institute of Nuclear Research" Liu Lianfan et al. Nuclear Instruments & Methods in Physics Research, Section -B: Beam Interactions with Materials and Atoms, North-Holland Publishing Company. Amsterdam, NL, Bd. B52, Nr. 3/4 Pages 298-300					
SHV		9/1/1983 "A Versatile High Intensity Negative Ion Source" R. Middleton Nuclear Instruments and Methods, Bd. 214, Pages 139-150					
SHV		1/2/1992 "The Hvee Tandetron Line; New Developments and Design Considerations" Mous D J W et al. Nuclear Instruments & Methods in Physics Research, Section -B: Beam Interactions with Materials and Atoms, North-Holland Publishing Company. Amsterdam, NL, Bd. B62, Nr. 3 Pages 421-424					
SHV		2/1/1993 "Ion Sources for Accelerators in Materials Research" Alton G D Nuclear Instruments & Methods in Physics Research, Section -B: Beam Interactions with Materials and Atoms, North-Holland Publishing Company. Amsterdam, NL Bd. B73, Nr. 2. Pages 221-288					
EXAMINER 				DATE CONSIDERED 			
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Form PTO-1449 (Rev. 7-80) 42-44F (F-49)		U.S. Department of Commerce Patent and Trademark Office		Atty. Docket No.: F-7904		Serial No.: UNKNOWN 19/65,8%	
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OTHER INFORMATION DISCLOSURE CITATIONS (Including Author, Title, Date, Pertinent Pages, Etc.)							
SHV		1993; Ion Sources For Accelerators In Materials Research; G.D. Alton; Nuclear Instruments and Methods in Physics Research; pgs. 221-288					
SHV		4/2/93; Sputter Ion Source; High Voltage Engineering Europa B.V.; pgs. 1-18					
EXAMINER 				DATE CONSIDERED April 18, 2005			
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